

# Ultra Fast NPT - IGBT® with Ultra Soft Recovery Diode

The Ultra Fast 650V NPT-IGBT® family of products is the newest generation of IGBTs optimized for outstanding ruggedness and best trade-off between conduction and switching losses.

## **Features**

- Low Saturation Voltage
- Low Tail Current
- RoHS Compliant
- Smooth Reverse Recovery
- Short Circuit Withstand Rated
- High Frequency Switching
- Ultra Low Leakage Current
- · Snap-free Switching



Unless stated otherwise, Microsemi discrete IGBTs contain a single IGBT die. This device is recommended for applications such as induction heating (IH), motor control, general purpose inverters and uninterruptible power supplies (UPS).

## **MAXIMUM RATINGS**

All Ratings:  $T_C = 25^{\circ}C$  unless otherwise specified.

Symbol	Parameter	Ratings	Unit
V <sub>CES</sub>	Collector Emitter Voltage	650	V
$V_{\rm GE}$	Gate-Emitter Voltage	±30	V
I <sub>C1</sub>	Continuous Collector Current @ T <sub>c</sub> = 25°C	118	
I <sub>C2</sub>	Continuous Collector Current @ T <sub>C</sub> = 110°C	56	Α
I <sub>CM</sub>	Pulsed Collector Current ①	224	
SCWT	Short Circuit Withstand Time: $V_{CE} = 325V$ , $V_{GE} = 15V$ , $T_{C} = 125^{\circ}C$	10	μs
P <sub>D</sub>	Total Power Dissipation @ T <sub>c</sub> = 25°C	543	W
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to 150	°C
$T_L$	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300	C

## STATIC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Min	Тур	Max	Unit
V <sub>(BR)CES</sub>	Collector-Emitter Breakdown Voltage $(V_{GE} = 0V, I_{C} = 350\mu\text{A})$	650			
V <sub>GE(TH)</sub>	Gate Threshold Voltage $(V_{CE} = V_{GE}, I_{C} = 2.5 \text{mA}, T_{j} = 25 ^{\circ}\text{C})$	3.5	5.0	6.5	
V <sub>CE(ON)</sub>	Collector-Emitter On Voltage ( $V_{GE} = 15V$ , $I_{C} = 45A$ , $T_{j} = 25^{\circ}C$ )		1.9	2.4	Volts
	Collector-Emitter On Voltage ( $V_{GE} = 15V$ , $I_{C} = 45A$ , $T_{j} = 125$ °C)		2.4		
	Collector-Emitter On Voltage $(V_{GE} = 15V, I_{C} = 90A, T_{j} = 25^{\circ}C)$		2.6		İ
I <sub>CES</sub>	Collector Cut-off Current $(V_{CE} = 650V, V_{GE} = 0V, T_j = 25^{\circ}C)$ ②		20	350	
	Collector Cut-off Current (V <sub>CE</sub> = 650V, V <sub>GE</sub> = 0V, T <sub>j</sub> = 125°C) ②		200		μA
I <sub>GES</sub>	Gate-Emitter Leakage Current (V <sub>GE</sub> = ±20V)			±250	nA

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C <sub>ies</sub>	Input Capacitance	Capacitance		2900		
C <sub>oes</sub>	Output Capacitance	$V_{GE} = 0V, V_{CE} = 25V$		548		pF
C <sub>res</sub>	Reverse Transfer Capacitance	f = 1MHz		268		
$V_{GEP}$	Gate to Emitter Plateau Voltage	Gate Charge		7.5		V
Q <sup>③</sup>	Total Gate Charge	V <sub>GE</sub> = 15V		150	203	
$Q_{ge}$	Gate-Emitter Charge	V <sub>CE</sub> = 325V		18	24	nC
$Q_{gc}$	Gate- Collector Charge	I <sub>C</sub> = 45A		74	100	
t <sub>d(on)</sub>	Turn-On Delay Time	Inductive Switching (25°C)		15		
t <sub>r</sub>	Current Rise Time	V <sub>CC</sub> = 433V		32		ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GE</sub> = 15V		100		
t <sub>f</sub>	Current Fall Time	I <sub>C</sub> = 45A		50		
E <sub>on2</sub> ⑤	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3\Omega^{(4)}$		1100	1650	1
E <sub>off</sub>	Turn-Off Switching Energy	T <sub>J</sub> = +25°C		540	870	μJ
t <sub>d(on)</sub>	Turn-On Delay Time	Inductive Switching (125°C)		15		
t <sub>r</sub>	Current Rise Time	V <sub>CC</sub> = 433V		32		
$t_{d(off)}$	Turn-Off Delay Time	V <sub>GE</sub> = 15V		123		ns
t <sub>f</sub>	Current Fall Time	I <sub>C</sub> = 45A		52		
E <sub>on2</sub> 5	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3\Omega^{(4)}$		1600	2400	1
E <sub>off</sub>	Turn-Off Switching Energy	T <sub>J</sub> = +125°C		800	1160	μJ

#### THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	Min	Тур	Max	Unit
R <sub>eJC</sub>	Junction to Case Thermal Resistance (IGBT)			0.23	°C/W
	Junction to Case Thermal Resistance (Diode)			0.80	
R <sub>eJA</sub>	Junction to Ambient Thermal Resistance			40	
W <sub>T</sub>	Package Weight		0.22		oz
			6.2		g

- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- 2 Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- 3 See Mil-Std-750 Method 3471.
- 4 R<sub>c</sub> is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)
- 5  $\rm E_{on2}$  is the energy loss at turn-on and includes the charge stored in the freewheeling diode.

6 E<sub>off</sub> is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

## **TYPICAL PERFORMANCE CURVES**

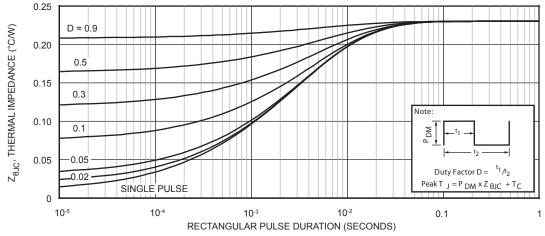


FIGURE 1, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

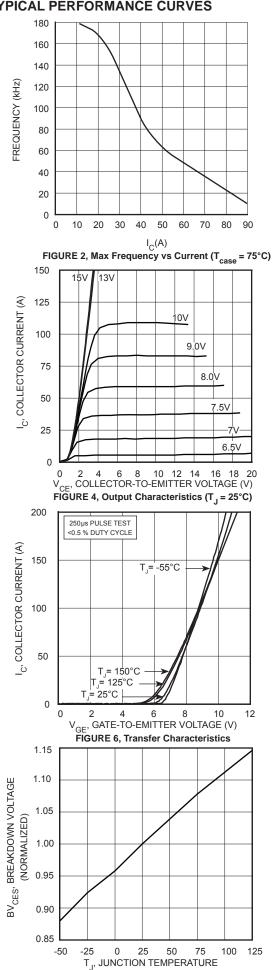


FIGURE 8, Breakdown Voltage vs Junction Temperature

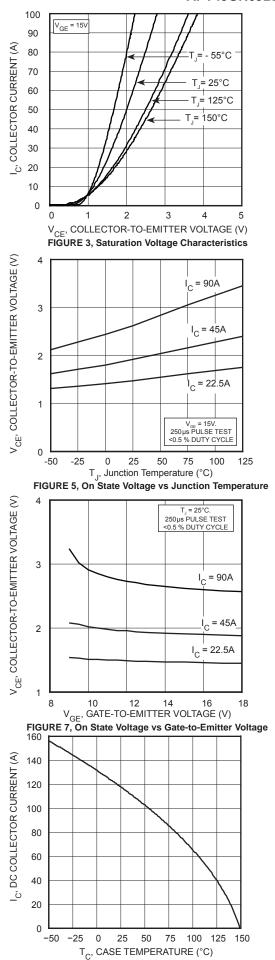
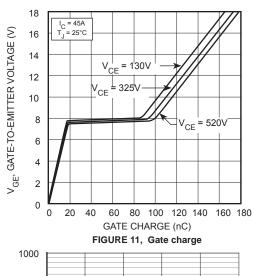
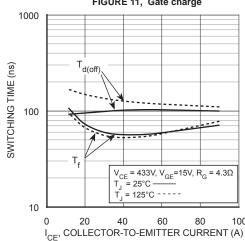
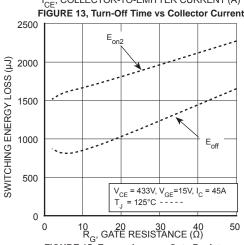


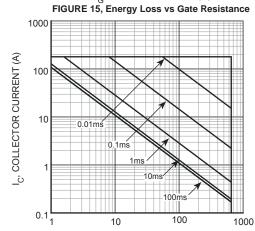
FIGURE 9, DC Collector Current vs Case Temperature

FIGURE 16, Swiitching Energy vs Junction Temperature









 $V_{CE}$ , COLLECTOR-TO-EMITTER VOLTAGE FIGURE 17, Minimum Switching Safe Operating Area

# **ULTRA SOFT RECOVERY ANTI-PARALLEL DIODE**

## **MAXIMUM RATINGS**

All Ratings: T<sub>C</sub> = 25°C unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT45GR65B2DU30	Unit
I <sub>F(AV)</sub>	Maximum Average Forward Current (T <sub>c</sub> = 82°C, Duty Cycle = 0.5)	30	
I <sub>F(RMS)</sub>	RMS Forward Current (Square wave, 50% duty)	41	Amps
I <sub>FSM</sub>	Non-Repetitive Forward Surge Current (T <sub>J</sub> = 45°C, 8.3ms)	210	

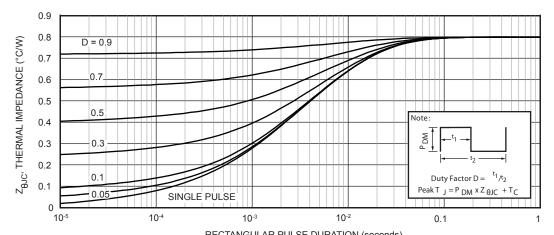
## STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions		Min	Тур	Max	Unit
V <sub>F</sub>	Forward Voltage	I <sub>F</sub> = 30A		3		
		I <sub>F</sub> = 60A		3.9		Volts
		I <sub>F</sub> = 60A, T <sub>J</sub> = 125°C		3.5		

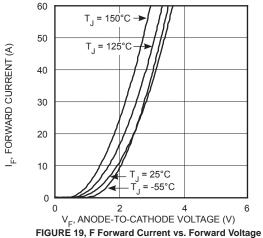
## **DYNAMIC CHARACTERISTICS**

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 1.0A$ , dif/dt= -100 A/µs, $V_R = 30V$ , $T_j = 25$ °C		28		ns
t <sub>rr</sub>	Reverse Recovery Time	I <sub>=</sub> = 30 Amps		80		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dif/dt= -200 A/µs		110		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current	V <sub>R</sub> = 433 Volts		3		Amps
E <sub>rr</sub>	Reverse Recovery Energy	T <sub>j</sub> = 25°C		2		μJ
t <sub>rr</sub>	Reverse Recovery	$I_{F} = 30 \text{ Amps}$ $dif/dt = -200 \text{ A/}\mu\text{s}$ $V_{R} = 433 \text{ Volts}$ $T_{J} = 125^{\circ}\text{C}$		343		ns
Q <sub>rr</sub>	Reverse Recovery Charge			965		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current			7		Amps
E <sub>rr</sub>	Reverse Recovery Energy			88		μJ
t <sub>rr</sub>	Reverse Recovery	$I_{\rm F}$ = 30 Amps dif/dt= -1000 A/µs $V_{\rm R}$ = 433 Volts $T_{\rm J}$ = 125°C		124		ns
Q <sub>rr</sub>	Reverse Recovery Charge			1355		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current			24		Amps
E <sub>rr</sub>	Reverse Recovery Energy			211		μJ
S	Softness Factor (t <sub>b</sub> /t <sub>a</sub> )	$I_F = 15A$ , dif/dt= -1000 A/ $\mu$ s, $V_R = 800V$ , $T_j = 125$ °C		2		

## **TYPICAL PERFORMANCE CURVES**



RECTANGULAR PULSE DURATION (seconds)
FIGURE 18, MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs. PULSE DURATION



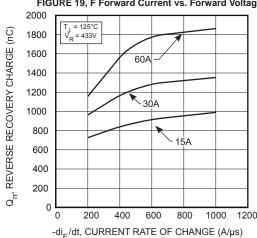
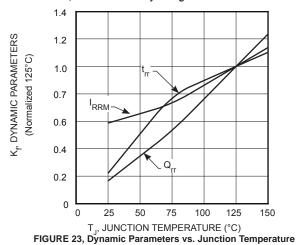


FIGURE 21, Reverse Recovery Charge vs. Current Rate of Change



 ${\rm V_R, REVERSE\ VOLTAGE\ (V)}$  FIGURE 25, Junction Capacitance vs. Reverse Voltage

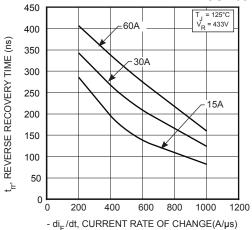


FIGURE 20, Reverse Recovery Time vs. Current Rate of Change

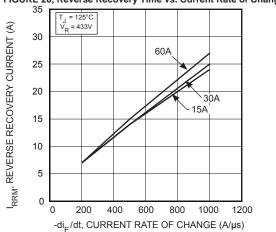


FIGURE 22, Reverse Recovery Current vs. Current Rate of Change

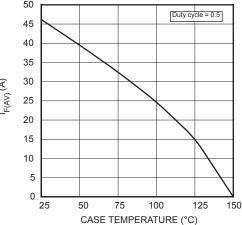
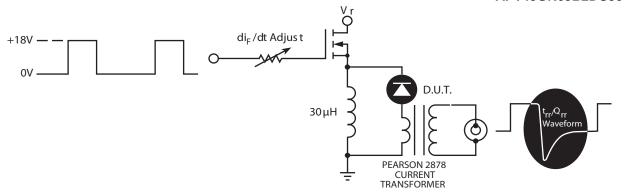


FIGURE 24, Max Average Forward Current vs. Case Temperature

#### APT45GR65B2DU30

6

0.25 I<sub>RRM</sub>



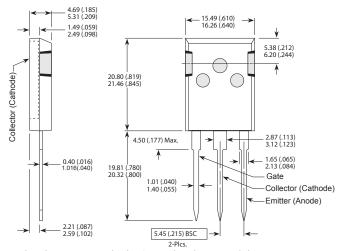
Zero 1

FIGURE 26, Diode Test Circuit

- 1 I<sub>F</sub> Forward Conduction Current
- 2 di<sub>F</sub>/dt Rate of Diode Current Change Through Zero Crossing
- 3 I<sub>RRM</sub> Maximum Reverse Recovery Current
- $oldsymbol{4}$   $extstyle{t}_{_{\! A}}$  Time to reach Maximum Reverse Recovery Current ( $extstyle{I}_{_{\! RRM}}$ )
- $_{\rm b}$  Time from Maximum Reverse Recovery Current ( $I_{\rm RRM}$ ) to projected zero crossing based on a straight line from  $I_{\rm RRM}$  through 25%  $I_{\rm RRM}$ .
- 6 t<sub>rr</sub> Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I<sub>RRM</sub> and 0.25, I<sub>RRM</sub> passes through zero
- $\mathbf{Q}_{rr}$  Area Under the Curve Defined by  $\mathbf{I}_{RRM}$  and  $\mathbf{t}_{rr}$

FIGURE 27, Diode Reverse Recovery Waveform Definition

## T-MAX® (B2) Package Outline



These dimensions are equal to the TO-247 without the mounting hole.

Dimensions in Millimeters and (Inches)

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